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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128253	APPLICATION NO. New U.S. National Stage 6 PCT/JP2004/018435 10/581507
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		APPLICANTS Hiroyuki NAGASAKA et al.		
		FILING DATE June 1, 2006		

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/AM/	8.	JP-A-2003-240906	08/27/2003	JAPAN	X	X
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EXAMINER /Alan Mathews/	DATE CONSIDERED 11/16/2009
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